



CHG Commands

This chapter provides CHG (change) commands for the Cisco ONS 15454, ONS 15327, ONS 15600 and ONS 15310-CL.

5.1 CHG-ACCMD-<MOD_TACC>

Change Test Access Mode (DS1, STS1, STS12C, STS192C, STS24C, STS3C, STS48C, STS6C, STS9C, T1, T3, VT1, VT2)

Usage Guidelines

Cisco ONS 15454, ONS 15327, ONS 15600

See [Table 27-1 on page 27-1](#) for supported modifiers by platform.

This command changes the test access (TACC) mode for the circuit being tested. For more information about TACC, refer to the [Cisco ONS SONET TL1 Reference Guide](#).

This can be a change from monitoring the data to inserting data into the STS. This command can only be applied to an existing TAP connection.



Caution

For this command to be applicable, you must first create the TAP using the ED-<MOD_PATH> command. Intrusive test access modes are traffic-affecting. If a facility/path is connected to a TAP in an intrusive test access mode, it is forced to go into the OOS-MT state. The forced transition could be traffic-affecting. The present state of the facility/path is stored by the NE and is restored when the TAP connection is terminated. Test access connections are dropped automatically if the TL1 session is terminated or is timed out.



Note

- If there is no TAP connection, a DENY error message is returned.
- If a requested condition already exists, a SRCN error message is returned.
- If a requested access configuration is invalid, a SRAC error message is returned.
- If a requested TAP does not exist, a RTEN error message is returned.

Category

Troubleshooting and Test Access

Security

Maintenance

Related Commands

CONN-TACC-<MOD_TACC> DISC-TACC RTRV-TACC

Input Format

CHG-ACCMD-<MOD_TACC>:[<TID>]:<TAP>: <CTAG>::<MD>;

Input Example

CHG-ACCMD-STS1:CISCO:8:123::MONE;

Input Parameters**Table 5-1** *CHG-ACCMD-<MOD_TACC> Input Parameters*

Parameter and Values	Description
TAP	The Test Access Path number. TAP number must be an integer with a range of 1 to 999. String Note This command only supports changing the mode for a single TAP number at a time.
MD	The test access mode. (SPLTE, SPLTF, LOOPE and LOOPF require an external QRS input signal.) Single FAD Test Access does not support MONEF, SPLTEF & SPLTAB modes Parameter type is TACC_MODE—test access mode
• LOOPE	Splits both the A and B paths. Connect the line incoming from E direction to the line outgoing in the E direction, and connect this looped configuration to the FAD. The line outgoing in the F direction will have a QRS connected, and the line incoming from the F direction will be terminated by the nominal characteristic impedance of the line. Intrusive test access mode
• LOOPF	Splits both the A and B paths. Connect the line incoming from F direction to the line outgoing in the F direction, and connect this looped configuration to the FAD. The line outgoing in the E direction will have a QRS connected, and the line incoming from the E direction will be terminated by the nominal characteristic impedance of the line. Intrusive test access mode
• MONE	Indicates that a monitor connection will be provided from the FAD to the A transmission path of the accessed circuit
• MONEF	Indicates that a monitor connection will be provided: - From the FAD1 to a DFAD, or the odd pair of a FAP, to the A transmission path and - From the FAD2 of the same DFAD, or the even pair of a FAP, to the B transmission path of the accessed circuit.
• MONF	Indicates that a monitor connection will be provided from the FAD to the B transmission path of the accessed circuit.
• SPLTA	Indicates that a connection will be provided from both the E and F sides of the A transmission path of the circuit under test to the FAD and split the A transmission path. Intrusive test access mode

Table 5-1 CHG-ACCMD-<MOD_TACC> Input Parameters (continued)

Parameter and Values	Description
SPLTB	Indicates that a connection will be provided from both the E and F sides of the B transmission path of the circuit under test to the FAD and split the B transmission path. Intrusive test access mode
SPLTE	Splits both the A and B paths and connect the E side of the accessed circuit to the FAD. The line outgoing in the F direction will have a QRS connected, and the line incoming from the F direction will have a QRS connected, and the line incoming from the E direction will be terminated by the nominal characteristic impedance of the line. Intrusive test access mode
SPLTEF	Splits both the A and B paths, and connect the E side of the accessed circuit to FAD1 and the F side to FAD2. Intrusive test access mode
SPLTF	Splits both the A and B paths, and connect the F side of the accessed circuit to the FAD. The line outgoing in the E direction will have a QRS connected, and the line incoming in the E direction will have a QRS connected, and the line incoming from the E direction will be terminated by the nominal characteristic impedance of the line. Intrusive test access mode

5.2 CHG-EQPT

Change Equipment

Usage Guidelines

Cisco ONS 15454

This command performs an in-service upgrade from low density (LD) electrical cards DS1 (DS1-14, DS1N-14), DS3 (DS3-12, DS3N-12, DS3NE-12), EC1, and DS3XM-6 to high density (HD) electrical cards DS1/E1-56, DS3/EC1-48 and DS3XM-12 respectively, is supported by this command.



Note

- For Release 6.0, only limited upgrades are supported, such as upgrading one LD DS3-12 card to one HD DS3/EC1-48 card.
- Optical (OC-N) card upgrades are not supported in Release 6.0.
- Compatible equipment types for card upgrade are
 - DS3XM-6 to DS3XM-12
 - DS-3/DS3-N/DS3-E/DS3N-E to DS3/EC1-48
 - DS-1/DS1-N to DS1/E1-56
- Provisioning Rules for card upgrade:
 - DS1-14 and DS1N-14 provisioned on one of Slots 1, 2, 3, 15, 16, and 17 should be upgraded to DS1-E1-56.
 - DS1-14 or DSN-14 provisioned in Slots 4, 5, 6, 12, 13, and 14 will fail when upgrading to DS1-56.

- DS3-12/DS3N-12/DS3E-12/DS3NE-12 in Slots 1, 2, 3, 15, 16, and 17 can be upgraded to DS3/EC1-48 card and will fail on slots 4, 5, 6, 12, 13, and 14.
- Two upgradable cards provisioned in a 1:1 protection group cannot be upgraded.

Category

Equipment

Security

Maintenance

Related Commands

ALW-SWDX-EQPT	REPT ALM EQPT	RTRV-ALMTH-EQPT
ALW-SWTOPROTN-EQPT	REPT EVT EQPT	RTRV-COND-EQPT
ALW-SWTOWKG-EQPT	REPT RMV EQPT	RTRV-EQPT
DLT-EQPT ED-EQPT	REPT RST EQPT	SET-ALMTH-EQPT
ENT-EQPT	RMV-EQPT	SW-DX-EQPT
INH-SWDX-EQPT	RST-EQPT	SW-TOPROTN-EQPT
INH-SWTOPROTN-EQPT	RTRV-ALM-EQPT	SW-TOWKG-EQPT
INH-SWTOWKG-EQPT		

Input Format

CHG-EQPT:[<TID>]:<SRC>:<CTAG>::<EQPTTYPE>;

Input Example

CHG-EQPT::SLOT-1:1::DS3-EC1-48;

Input Parameters**Table 5-2 CHG-EQPT Input Parameters**

Parameter and Values	Description
SRC	The source access identifier from the “25.1.13 EQPT” section on page 25-27
EQPTTYPE	The equipment type to be upgraded Parameter type is EQUIPMENT_TYPE—equipment type
• DS1-14	DS1-14 card
• DS1N-14	DS1N-14 card
• DS3-12	DS3-12card
• DS3-EC1-48	DS3-EC1-48 card
• DS3N-12	DS3N-12 card
• DS3NE-12	DS3NE-12 card
• EC1	EC1 card

Table 5-2 CHG-EQPT Input Parameters (continued)

Parameter and Values	Description
• DS3XM-6	DS3XM-6 card
• DS3XM-12	DS3XM-12 card

